Document Title
4Bank x 2M x32Bit Synchronous DRAM

## Revision History

| Revision No. | History | Draft Date | Remark |
| :---: | :--- | :---: | :---: |
| 0.1 | Initial Draft | May. 2003 | Preliminary |
| 0.2 | 1) Deleted Preliminary <br> 2) Defined Input/Output Cap. Spec. | Dec. 2003 |  |

[^0]
## DESCRIPTION

The Hynix HY5V52CFP is a $268,435,456$ bit CMOS Synchronous DRAM, ideally suited for the memory applications which require wide data I/O and high bandwidth. HY5V52CFP is organized as 4banks of 2,097,152x32.

HY5V52CFP is offering fully synchronous operation referenced to a positive edge of the clock. All inputs and outputs are synchronized with the rising edge of the clock input. The data paths are internally pipelined to achieve very high bandwidth. All input and output voltage levels are compatible with LVTTL.

Programmable options include the length of pipeline (Read latency of 2 or 3 ), the number of consecutive read or write cycles initiated by a single control command (Burst length of $1,2,4,8$ or full page), and the burst count sequence(sequential or interleave). A burst of read or write cycles in progress can be terminated by a burst terminate command or can be interrupted and replaced by a new burst read or write command on any cycle. (This pipelined design is not restricted by a $2 N^{`}$ rule.)

## FEATURES

- JEDEC standard 3.3V power supply
- All device pins are compatible with LVTTL interface
- 90Ball FBGA with 0.8 mm of pin pitch
- All inputs and outputs referenced to positive edge of system clock
- Data mask function by DQM0,1,2 and 3
- Internal four banks operation
- Auto refresh and self refresh
- 4096 refresh cycles / 64ms
- Programmable Burst Length and Burst Type

$$
-1,2,4,8 \text { or full page for Sequential Burst }
$$

- 1, 2, 4 or 8 for Interleave Burst
- Programmable $\overline{\mathrm{CAS}}$ Latency ; 2, 3 Clocks
- Burst Read Single Write operation


## ORDERING INFORMATION

| Part No. | Clock Frequency | Organization | Interface | Package |
| :---: | :---: | :---: | :---: | :---: |
| HY5V52C(L)FP-6 | 166 MHz | $4 B a n k s \times 2 \mathrm{Mbits} \times 32$ | LVTTL | 90Ball FBGA |
| HY5V52C(L)FP-H | 133 MHz | $4 B a n k s \times 2 \mathrm{Mbits} \times 32$ | LVTTL | 90Ball FBGA |
| HY5V52C(L)FP-8 | 125 MHz | $4 B a n k s \times 2 \mathrm{Mbits} \times 32$ | LVTTL | $90 B a l l$ FBGA |
| HY5V52C(L)FP-P | 100 MHz | $4 B a n k s \times 2 \mathrm{Mbits} \times 32$ | LVTTL | 90Ball FBGA |
| HY5V52C(L)FP-S | 100 MHz | $4 B a n k s \times 2 M b i t s \times 32$ | LVTTL | 90Ball FBGA |

[^1]
## Ball CONFIGURATION



## Ball DESCRIPTION

| PIN | PIN NAME | DESCRIPTION |
| :---: | :---: | :---: |
| CLK | Clock | The system clock input. All other inputs are registered to the SDRAM on the rising edge of CLK. |
| CKE | Clock Enable | Controls internal clock signal and when deactivated, the SDRAM will be one of the states among power down, suspend or self refresh |
| $\overline{\mathrm{CS}}$ | Chip Select | Enables or disables all inputs except CLK, CKE and DQM |
| BA0, BA1 | Bank Address | Selects bank to be activated during $\overline{\text { RAS activity }}$ Selects bank to be read/written during CAS activity |
| A0 ~ A11 | Address | Row Address : RA0 ~ RA11, Column Address : CA0 ~ CA8 Auto-precharge flag : A10 |
| $\overline{\mathrm{RAS}}, \overline{\mathrm{CAS}}, \overline{\mathrm{WE}}$ | Row Address Strobe, Column Address Strobe, Write Enable | $\overline{\mathrm{RAS}}, \overline{\mathrm{CAS}}$ and $\overline{\mathrm{WE}}$ define the operation Refer function truth table for details |
| DQM0~3 | Data Input/Output Mask | Controls output buffers in read mode and masks input data in write mode |
| DQ0 ~ DQ31 | Data Input/Output | Multiplexed data input / output pin |
| VDD/VSS | Power Supply/Ground | Power supply for internal circuits and input buffers |
| VDDQ/VSSQ | Data Output Power/Ground | Power supply for output buffers |
| NC | No Connection | No connection |

## ABSOLUTE MAXIMUM RATINGS

| Parameter | Symbol | Rating | Unit |
| :--- | :--- | :--- | :--- |
| Ambient Temperature | TA | $0 \sim 70$ | ${ }^{\circ} \mathrm{C}$ |
| Storage Temperature | TSTG | $-55 \sim 125$ | ${ }^{\circ} \mathrm{C}$ |
| Voltage on Any Pin relative to VSS | VIN, VoUT | $-1.0 \sim 4.6$ | V |
| Voltage on VDD relative to VSS | VDD, VDDQ | $-1.0 \sim 4.6$ | V |
| Short Circuit Output Current | IOS | 50 | mA |
| Power Dissipation | PD | $260 \cdot 10$ | W |
| Soldering Temperature • Time | TSOLDER |  | ${ }^{\circ} \mathrm{C} \cdot \mathrm{Sec}$ |

Note : Operation at above absolute maximum rating can adversely affect device reliability

## DC OPERATING CONDITION (TA $=0$ to $70^{\circ} \mathrm{C}$ )

| Parameter | Symbol | Min | Typ. | Max | Unit | Note |
| :--- | :--- | :---: | :---: | :---: | :---: | :---: |
| Power Supply Voltage | VDD, VDDQ | 3.135 | 3.3 | 3.6 | $V$ | 1 |
| Input high voltage | VIH | 2.0 | 3.0 | VDDQ +0.3 | $V$ | 1,2 |
| Input low voltage | VIL | VSSQ -0.3 | 0 | 0.8 | $V$ | 1,3 |

## Note:

1.All voltages are referenced to $\mathrm{VSS}=0 \mathrm{~V}$
2. VIH (max) is acceptable 5.6 V AC pulse width with $\leq 3 \mathrm{~ns}$ of duration with no input clamp diodes
3. VIL ( min ) is acceptable -2.0 V AC pulse width with $\leq 3 \mathrm{~ns}$ of duration with no input clamp diodes

## AC OPERATING CONDITION (TA $=0$ to $70^{\circ} \mathrm{C}, 3.0 \mathrm{~V} \leq \mathrm{VDD} \leq 3.6 \mathrm{~V}, \mathrm{Vss}=0 \mathrm{~V}$ - Note 1 )

| Parameter | Symbol | Value | Unit | Note |
| :--- | :---: | :---: | :---: | :---: |
| AC input high / low level voltage | $\mathrm{VIH} / \mathrm{VIL}$ | $2.4 / 0.4$ | V |  |
| Input timing measurement reference level voltage | Vtrip | 1.4 | V |  |
| Input rise / fall time | $\mathrm{tR} / \mathrm{tF}$ | 1 | ns |  |
| Output timing measurement reference level | Voutref | 1.4 | V |  |
| Output load capacitance for access time measurement | CL | 30 | pF |  |

## Note

1.Output load to measure access times is equivalent to two TTL gates and one capacitor (30pF) For details, refer to AC/DC output load circuit

CAPACITANCE ( $\mathrm{TA}=25^{\circ} \mathrm{C}, \mathrm{f}=1 \mathrm{MHz}, \mathrm{VDD}=3.3 \mathrm{~V}$ )

| Parameter | Pin | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Input capacitance | CLK | CI1 | 5.0 | 7.0 | pF |
|  | A0 ~ A11, BA0, BA1, CKE, $\overline{\mathrm{CS}}, \overline{\mathrm{RAS}}, \overline{\mathrm{CAS}}, \overline{\mathrm{WE}}$, | Cl 2 | 5.0 | 8.0 | pF |
|  | DQMO~3 | Cl 3 | 2.5 | 5.0 | pF |
| Data input / output capacitance | DQ0 ~ DQ31 | $\mathrm{Cl} / \mathrm{O}$ | 4.0 | 6.5 | pF |

## OUTPUT LOAD CIRCUIT



DC CHARACTERISTICS I (DC operating conditions unless otherwise noted)

| Parameter | Symbol | Min. | Max | Unit | Note |
| :--- | :--- | :--- | :--- | :--- | :--- |
| Input leakage current | ILI | -1 | 1 | 1 |  |
| Output leakage current | ILO | -1 | 1 | uA |  |
| Output high voltage | VOH | 2.4 | - | V | $\mathrm{IOH}=-2 \mathrm{~mA}$ |
| Output low voltage | VOL | - | 0.4 | V | $\mathrm{IOL}=+2 \mathrm{~mA}$ |

## Note:

1. $\mathrm{VIN}=0$ to 3.6 V , All other pins are not under test $=0 \mathrm{~V}$
2.DOUT is disabled, VOUT=0 to 3.6 V

DC CHARACTERISTICS II (DC operating conditions unless otherwise noted)

| Parameter | Symbol | Test Condition |  | speed |  |  |  |  | Unit | Note |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | -6 | -H | -8 | -P | S |  |  |
| Operating Current | IDD1 | Burst length=1, One bank active $\mathrm{tRC} \geq \mathrm{tRC}(\mathrm{min}), \mathrm{IOL}=0 \mathrm{~mA}$ |  | 260 | 240 |  | 220 |  | mA | 1 |
| Precharge Standby Current in power down mode | IDD2P | $\mathrm{CKE} \leq \mathrm{VIL}(\mathrm{max}), \mathrm{tCK}=10 \mathrm{~ns}$ |  | 4 |  |  |  |  | mA |  |
|  | IDD2PS | CKE $\leq$ VIL (max), tCK $=\infty$ |  | 2 |  |  |  |  |  |  |
| Precharge Standby Current in non power down mode | IDD2N | $\mathrm{CKE} \geq \mathrm{VIH}(\mathrm{min}), \overline{\mathrm{CS}} \geq \mathrm{VIH}(\mathrm{min}), \mathrm{tCK}=10 \mathrm{~ns}$ Input signals are changed one time during 2clks. All other pins $\geq$ VDD -0.2 V or $\leq 0.2 \mathrm{~V}$ |  | 30 |  |  |  |  | mA |  |
|  | IDD2NS | $\mathrm{CKE} \geq \mathrm{VIH}(\mathrm{min}), \mathrm{tCK}=\infty$ Input signals are stable. |  | 30 |  |  |  |  |  |  |
| Active Standby Current in power down mode | IDD3P | $\mathrm{CKE} \leq \mathrm{VIL}(\mathrm{max}), \mathrm{tCK}=10 \mathrm{~ns}$ |  | 10 |  |  |  |  | mA |  |
|  | IDD3PS | CKE $\leq$ VIL(max), tCK $=\infty$ |  | 10 |  |  |  |  |  |  |
| Active Standby Current in non power down mode | IDD3N | $\mathrm{CKE} \geq \mathrm{VIH}(\mathrm{min}), \overline{\mathrm{CS}} \geq \mathrm{VIH}(\mathrm{min}), \mathrm{tCK}=10 \mathrm{~ns}$ Input signals are changed one time during 2clks. All other pins $\geq$ VDD- 0.2 V or $\leq 0.2 \mathrm{~V}$ |  | 60 |  |  |  |  | mA |  |
|  | IDD3NS | $\mathrm{CKE} \geq \mathrm{VIH}($ min $), \mathrm{tCK}=\infty$ Input signals are stable. |  | 40 |  |  |  |  |  |  |
| Burst Mode Operating Current | IDD4 | $\mathrm{ttCK} \geq \mathrm{tCK}$ (min), IOL=OmA <br> All banks active | $C L=3$ | 300 | 260 |  | 220 |  | mA | 1 |
|  |  |  | CL=2 | 320 | 280 |  | 240 |  |  |  |
| Auto Refresh Current | IDD5 | tRC $\geq$ tRC(min), All banks active |  | 480 | 440 | 400 |  |  | mA | 2 |
| Self Refresh Current | IDD6 | CKE $\leq 0.2 \mathrm{~V}$ |  | 4 |  |  |  |  | mA | 3 |
|  |  |  |  | 1.6 |  |  |  |  |  | 4 |

## Note :

1.IDD1 and IDD4 depend on output loading and cycle rates. Specified values are measured with the output open
2.Min. of tRRC (Refresh $\overline{\text { RAS }}$ cycle time) is shown at AC CHARACTERISTICS II
3.HY5V52CFP-6/H/8/P/S
4.HY5V52CL:FP-6/H/8/P/S

AC CHARACTERISTICS I (AC operating conditions unless otherwise noted)

| Parameter |  | Symbol | -6 |  | -H |  | -8 |  | -P |  | -S |  | Unit | Note |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max |  |  |
| System clock cycle time | $\overline{\text { CAS }}$ Latency $=3$ |  | tCK3 | 6 | 1000 | 7.5 | 1000 | 8 | 1000 | 10 | 1000 | 10 | 1000 | ns |  |
|  | $\overline{\text { CAS }}$ Latency $=2$ | tCK2 | 10 | 10 |  | -10 |  | 10 |  | 12 |  | ns |  |  |
| Clock high pulse width |  | tCHW | 2.5 | - | 3 | - | 3 | - | 3 | - | 3 | - | ns | 1 |
| Clock low pulse width |  | tCLW | 2.5 | - | 3 | - | 3 | - | 3 | - | 3 | - | ns | 1 |
| Access time from clock | $\overline{\text { CAS }}$ Latency $=3$ | tAC3 | - | 5.4 | - | 5.5 | - | 6 | - | 6 | - | 6 | ns | 2 |
|  | $\overline{\text { CAS }}$ Latency $=2$ | tAC2 | - | 6 | - | 6 | - | 6 | - | 6 | - | 6 | ns |  |
| Data-out hold time |  | tOH | 2.7 | - | 2 | - | 2 | - | 2 | - | 2 | - | ns | 3 |
| Data-Input setup time |  | tDS | 1.5 | - | 1.75 | - | 2 | - | 2 | - | 2 | - | ns | 1 |
| Data-Input hold time |  | tDH | 0.8 | - | 1 | - | 1 | - | 1 | - | 1 | - | ns | 1 |
| Address setup time |  | tAS | 1.5 | - | 1.75 | - | 2 | - | 2 | - | 2 | - | ns | 1 |
| Address hold time |  | tAH | 0.8 | - | 1 | - | 1 | - | 1 | - | 1 | - | ns | 1 |
| CKE setup time |  | tCKS | 1.5 | - | 1.75 | - | 2 | - | 2 | - | 2 | - | ns | 1 |
| CKE hold time |  | tCKH | 0.8 | - | 1 | - | 1 | - | 1 | - | 1 | - | ns | 1 |
| Command setup time |  | tCS | 1.5 | - | 1.75 | - | 2 | - | 2 | - | 2 | - | ns | 1 |
| Command hold time |  | tCH | 0.8 | - | 1 | - | 1 | - | 1 | - | 1 | - | ns | 1 |
| CLK to data output in low Z-time |  | tOLZ | 1 | - | 1 | - | 1 | - | 1 | - | 1 | - | ns |  |
| CLK to data output in high Z-time | $\overline{\text { CAS }}$ Latency $=3$ | tOHZ3 | 2.7 | 5.4 | - | 5.5 | - | 6 | - | 6 | - | 6 | ns |  |
|  | $\overline{\text { CAS }}$ Latency $=2$ | tOHZ2 | 2.7 | 5.4 | - | 6 | - | 6 | - | 6 | - | 6 | ns |  |

## Note:

1. Assume tR / tF (input rise and fall time) is 1 ns
2.Access times to be measured with input signals of $1 \mathrm{v} / \mathrm{ns}$ edge rate, 0.8 v to 2.0 v
3.Data-out hold time to be measured under 30pF load condition, without Vt termination

AC CHARACTERISTICS II (AC operating conditions unless otherwise noted)

| Parameter |  | Symbol | -6 |  | -H |  | -8 |  | -P |  | -S |  | Unit | Note |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max |  |  |
| $\overline{\mathrm{RAS}}$ cycle time | Operation |  | tRC | 60 | - | 63 | - | 64 | - | 70 | - | 70 | - | ns |  |
|  | Auto Refresh | tRRC | 60 | - | 63 | - | 64 | - | 70 | - | 70 | - | ns |  |
| $\overline{\mathrm{RAS}}$ to $\overline{\mathrm{CAS}}$ delay |  | tRCD | 18 | - | 20 | - | 20 | - | 20 | - | 20 | - | ns |  |
| $\overline{\mathrm{RAS}}$ active time |  | tRAS | 42 | 100K | 42 | 100K | 48 | 100K | 50 | 100K | 50 | 100K | ns |  |
| $\overline{\mathrm{RAS}}$ precharge time |  | tRP | 18 | - | 20 | - | 20 | - | 20 | - | 20 | - | ns |  |
| $\overline{\mathrm{RAS}}$ to $\overline{\mathrm{RAS}}$ bank active delay |  | tRRD | 12 | - | 2 | - | 2 | - | 20 | - | 20 | - | CLK |  |
| $\overline{\mathrm{CAS}}$ to $\overline{\mathrm{CAS}}$ delay |  | tCCD | 1 | - | 1 | - | 1 | - | 1 | - | 1 | - | CLK |  |
| Write command to data-in delay |  | tWTL | 0 | - | 0 | - | 0 | - | 0 | - | 0 | - | CLK |  |
| Data-in to precharge command |  | tDPL | 2 | - | 1 | - | 1 | - | 1 | - | 1 | - | CLK |  |
| Data-in to active command |  | tDAL | 5 | - | 4 | - | 4 | - | 4 | - | 4 | - | CLK |  |
| DQM to data-out Hi-Z |  | tDQZ | 2 | - | 2 | - | 2 | - | 2 | - | 2 | - | CLK |  |
| DQM to data-in mask |  | tDQM | 0 | - | 0 | - | 0 | - | 0 | - | 0 | - | CLK |  |
| MRS to new command |  | tMRD | 2 | - | 2 | - | 2 | - | 2 | - | 2 | - | CLK |  |
| Precharge to data output Hi-Z | $\overline{\text { CAS }}$ Latency $=3$ | tPROZ3 | 3 | - | 3 | - | 3 | - | 3 | - | 3 | - | CLK |  |
|  | $\overline{\mathrm{CAS}}$ Latency $=2$ | tPROZ2 | 2 | - | 2 | - | 2 | - | 2 | - | 2 | - | CLK |  |
| Power down exit time |  | tPDE | 1 | - | 1 | - | 1 | - | 1 | - | 1 | - | CLK |  |
| Self refresh exit tim |  | tSRE | 1 | - | 1 | - | 1 | - | 1 | - | 1 | - | CLK | 1 |
| Refresh Time |  | tREF | - | 64 | - | 64 | - | 64 | - | 64 | - | 64 | ms |  |

## Note:

1. A new command can be given tRRC after self refresh exit

HY5V52CFP
COMMAND TRUTH TABLE

| Command |  | CKEn-1 | CKEn | $\overline{\text { CS }}$ | $\overline{\text { RAS }}$ | $\overline{\text { CAS }}$ | $\overline{W E}$ | DQM | ADDR | $\begin{gathered} \text { A10/ } \\ \text { AP } \end{gathered}$ | BA | Note |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Mode Register Set |  | H | X | L | L | L | L | X | OP code |  |  |  |
| No Operation |  | H | X | H | X | X | X | X | X |  |  |  |
|  |  | L |  | H | H | H |  |  |  |  |  |
| Bank Active |  |  | H | X | L | L | H | H | X | RA |  | V |  |
| Read |  | H | X | L | H | L | H | X | CA | L | V |  |
| Read with Autopre |  |  |  |  |  |  |  |  |  | H |  |  |
| Write |  | H | X | L | H | L | L | X | CA | L | V |  |
| Write with Autopre |  |  |  |  |  |  |  |  |  | H |  |  |
| Precharge All Banks |  | H | X | L | L | H | L | X | X | H | X |  |
| Precharge selected |  |  |  |  |  |  |  |  |  | L | V |  |
| Burst Stop |  | H | X | L | H | H | L | X | X |  |  | 4 |
| DQM |  | H | X |  |  |  |  | V | X |  |  |  |
| Auto Refresh |  | H | H | L | L | L | H | X | X |  |  |  |
| Burst-Read-Single-WRITE |  | H | X | L | L | L | L | X | A9 Pin High (Other Pins OP code) |  |  | MRS <br> Mode |
| Self Refresh ${ }^{1}$ | Entry | H | L | L | L | L | H | X | X |  |  |  |
|  | Exit | L | H | H | X | X | X | X |  |  |  |  |
|  |  |  |  | L | H | H | H |  |  |  |  |  |
| Precharge power down | Entry | H | L | H | X | X | X | X | X |  |  |  |
|  |  |  |  | L | H | H | H |  |  |  |  |  |
|  | Exit | L | H | H | X | X | X | X |  |  |  |  |
|  |  |  |  | L | H | H | H |  |  |  |  |  |
| Clock Suspend | Entry | H | L | H | X | X | X | X | X |  |  |  |
|  |  |  |  | L | V | V | V |  |  |  |  |  |
|  | Exit | L | H | X |  |  |  | X |  |  |  |  |

## Note :

1. Exiting Self Refresh occurs by asynchronously bringing CKE from low to high
2. $\mathrm{X}=$ Don't care, $\mathrm{H}=$ Logic High, $\mathrm{L}=$ Logic Low. BA =Bank Address, RA = Row Address, CA = Column Address, Opcode $=$ Operand Code, NOP $=$ No Operation
3. The burst read sigle write mode is entered by programming the write burst mode bit (A9) in the mode register to a logic 1.
4. This command stops a full-page burst operation, and is illegal otherwise. Full page burst continues untill this command is input. When data input/output is completed for full-page of data, it automatically returns to the start address and input/output is performed repeatedly.

## BASIC FUNCTIONAL DESCRIPTION

## Mode Register

| BA1 | BA0 |  | A12 | A11 | A10 | A9 | A8 | A7 | A6 | A5 | A4 | A3 | A2 | A1 | A0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 0 | 0 |  | 0 | 0 | 0 | OP <br> CODE | 0 | 0 | CAS Latency | BT | Burst Length |  |  |  |  |

OP CODE

| A9 | Write Mode |
| :---: | :---: |
| 0 | Burst Read and Burst Write |
| 1 | Burst Read and Single Write |

Burst Type

| A3 | Burst Type |
| :---: | :---: |
| 0 | Sequential |
| 1 | Interleave |

## Burst Length

| A2 | A1 | A0 | Burst Length |  |
| :---: | :---: | :---: | :---: | :---: |
|  |  |  | $A 3=0$ | $A 3=1$ |
| 0 | 0 | 0 | 1 | 1 |
| 0 | 0 | 1 | 2 | 2 |
| 0 | 1 | 0 | 4 | 4 |
| 0 | 1 | 1 | 8 | 8 |
| 1 | 0 | 0 | Reserved | Reserved |
| 1 | 0 | 1 | Reserved | Reserved |
| 1 | 1 | 0 | Reserved | Reserved |
| 1 | 1 | 1 | Full Page | Reserved |

## PACKAGE INFORMATION

90Ball FBGA with 0.8 mm of pin pitch ( using 'Multi Chip Package' Technology)



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